



BELLE II GERMANY MEETING - AUGUST 2025

PXD EMERGENCY SHUTDOWN INVESTIGATION

paula.scholz@uni-bonn.de





Motivation

Simulation of PXD signal path

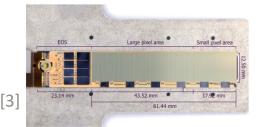
Lab-test: Fast-Shutdown signal transm.

Lab-test: Fast-Shutdown board modification



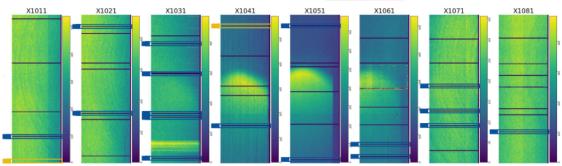
MOTIVATION

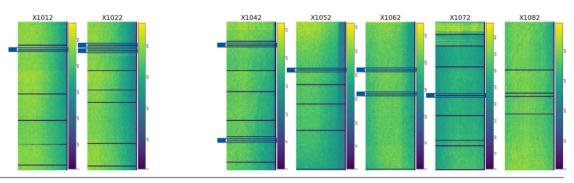
[4]



Switchers vulnerable to large radiation

- Example: Beam loss event in 2020
 - Estimated dose: 500 rad for PXD1 in 40 μs
 - Increased number of inefficient rows
 - In total 89 inefficient rows → efficiency drop of 3%
 - blue flags: freshly emerged inefficient rows
- Damage can be prevented when Switchers are turned off
- → Shutdown as fast and safe as possible

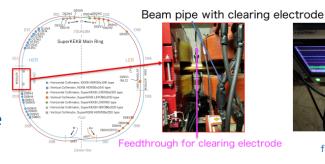






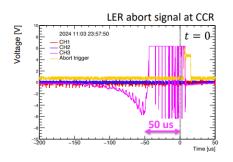
BEAM LOSS DETECTION

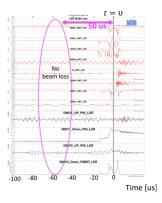
- New sensors, improved signal transmission
 - → Faster and earlier detection of SBLs
- Plan : Include signals into PXD interlock
 - → Lower threshold to put PXD into safe OFF state
- Candidate: Signal in clearing electrode
- Signal detected close to area where pressure burst occurred
- Strong correlation with SBLs
- Cable routing started (amplification and integration still TBD)
- To benefit from faster detection, we must minimise PXD shutdown delay





Monitor the signal from the feedthrough

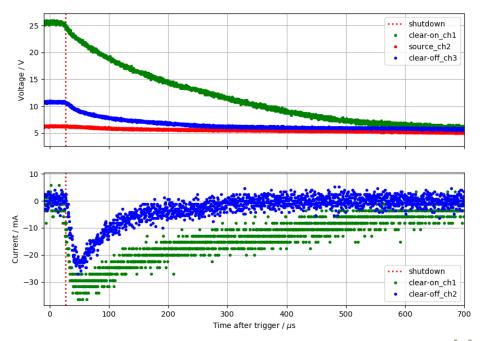






REGULAR SHUTDOWN

- Regular shutdown applied at PXD1:
 - Switch off power
- Example: Shutdown of Switcher voltages
- Long discharge time due to capacitors
 - Shutdown time in ms-range



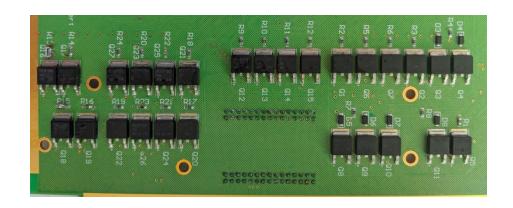
[4]



FAST SHUTDOWN BOARD

• <u>Idea</u>:

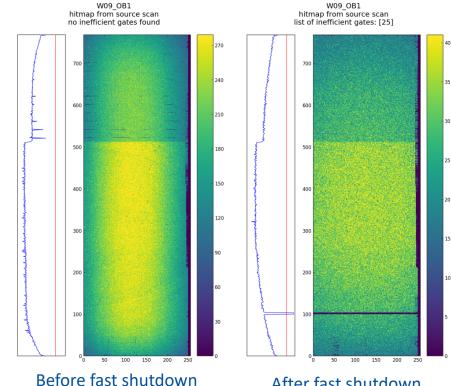
- Short all channels with FET (Field Effect Transistor) to respective ground
 - → Active pull-down
- Add resistor to influence pull-down time
- Problem:
 - Required resistor values unclear yet





RESULTS FROM FAST SHUTDOWN

- Testing of **fast shutdown** board resulted in high Switcher currents
- Example:
 - Compare hitmaps before and after using fast shutdown board
 - Detected inefficient rows
- If done wrongly:
 - Fast shutdown has same effects as a beam loss event



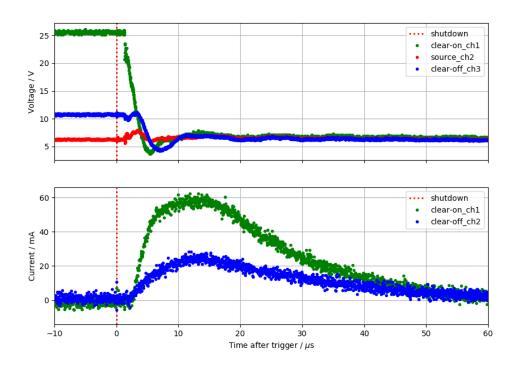
After fast shutdown

[5]



FAST SHUTDOWN MEASUREMENT

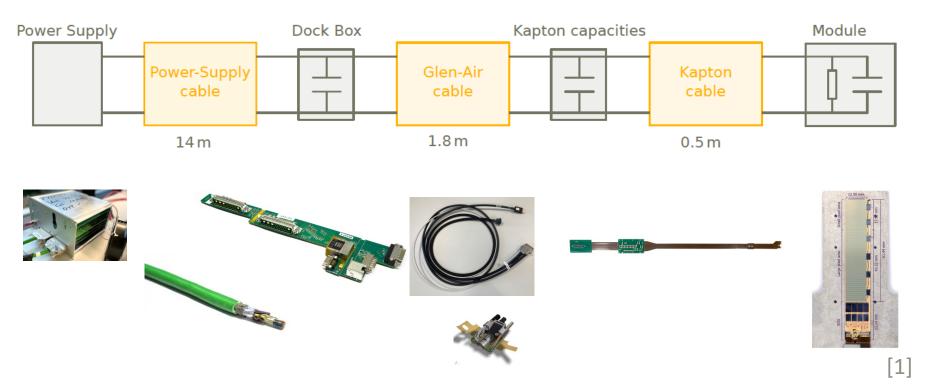
- <u>Example</u>: Shutdown of Switcher voltages (Clear On/ Clear Off), measured at Power Supply level
- $R_{ClearOn} = 0 \Omega$, $R_{ClearOff} = 0 \Omega$
- $V_{ClearOn}$ drops below $V_{ClearOff}$ ightharpoonup violation of shutdown sequence
- Testing on module is harmful







SIGNAL PATH



Belle II Germany Meeting '25 Paula Scholz 19



Motivation

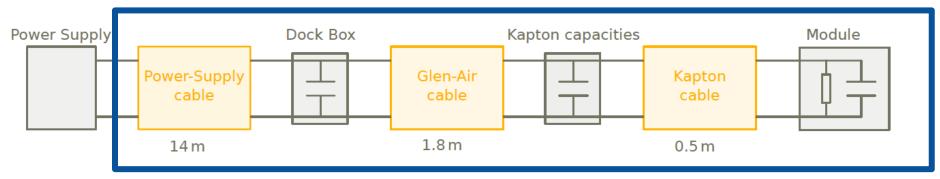
Simulation of PXD signal path

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SIGNAL PATH





[1]

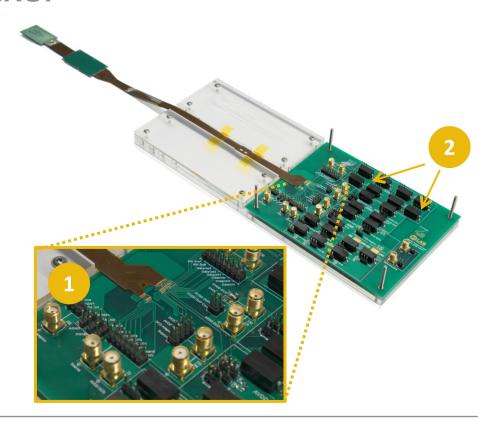


MODULE MOCKUP

- Verification of simulation: Module mockup PCB
 - Connection to all of the lines of Kapton 1



- Wire bonding necessary
- Module mockup 👩
 - Resistors and capacitors mimic module properties after the Kapton connection





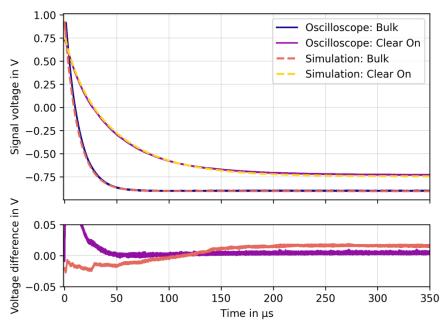
FULL CABLE PATH: POWERING OF TWO LINES

- Simulated with HyperLynx
- PXD PS is not simulated
- Not only powered lines need to be simulated because of capacitive coupling
- Replication of load with custom made PCB
- Compared to reference measurement
- Average voltage deviation:

Bulk line.: 8.7 mV

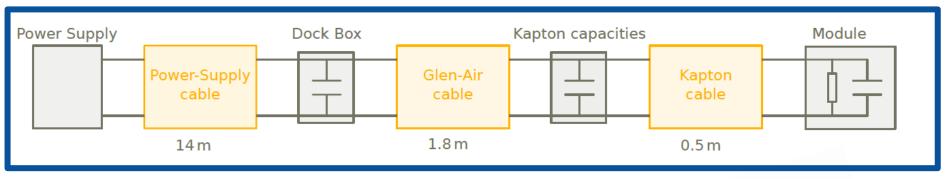
Clear On line: 13.26 mV







SIGNAL PATH







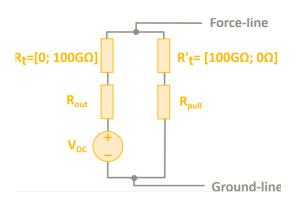
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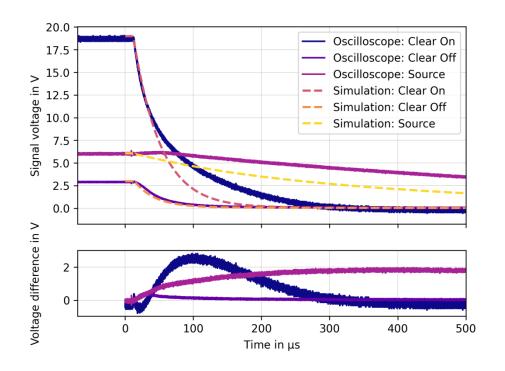


SHUTDOWN PROCEDURE

ACTIVE SHUTDOWN

- Active shutdown → **short** force and ground line
- Simulate by **time dependent resistor** which switches from 100 G Ω to 0 Ω

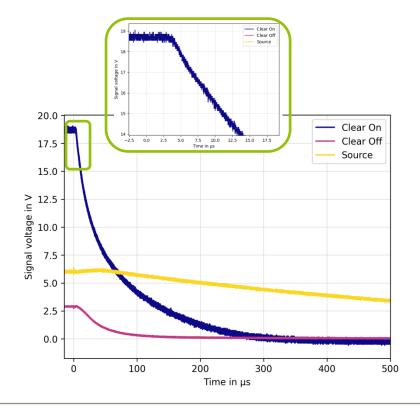






ACCELERATION OF FAST SHUTDOWN

- Two areas for improvement:
 - Clear-On signal only drops slowly
 - → generate steeper curve
 - Signal starts dropping ~4us after the shutdown-signal was sent
 - → decrease reaction time

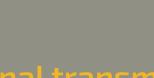




Motivation

Simulation of PXD signal path

Lab-test: Fast-Shutdown signal transm.





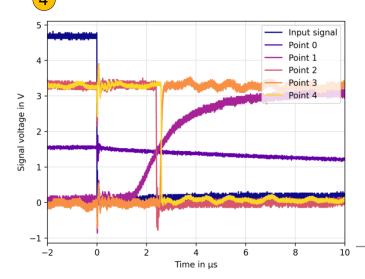


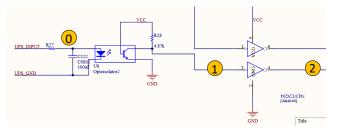


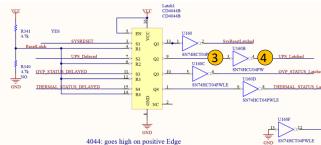


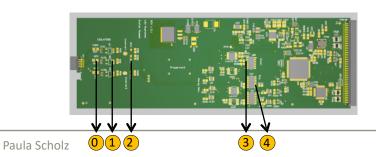
TRANSMISSION OF SHUTDOWN SIGNAL

- o after R27
- after optocoupler (PS8101-F3-A)
- after inverter (74LVC2G04)
- after NAND latch (CD4044B)
- after inverter (SN74HCU04PW)











Motivation

Simulation of PXD signal path

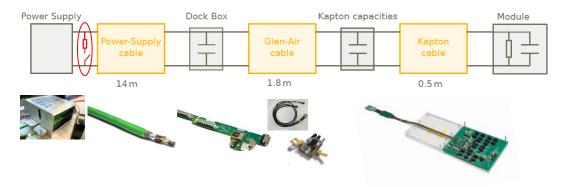
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Lab-test: Fast-Shutdown board modification



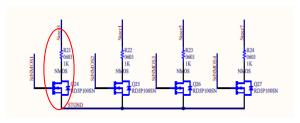
SETUP





- PS + Full cable path + Module Mockup
- External signal supplies fast shutdown signal
- Oscilloscope + active probes
- Measure Clear On and Clear Off voltage during fast shutdown with varying resistor values R_{on} and R_{off}

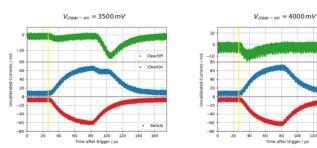


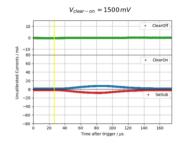


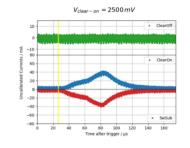


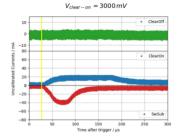
3V-LIMIT

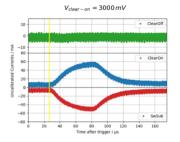
- Measured current in switcher (Clear On, Clear Off) for varying applied Clear On voltages
- Below V_{on} = 3V: no current flow between Clear On and Clear Off \rightarrow switcher is deemed 'safe'







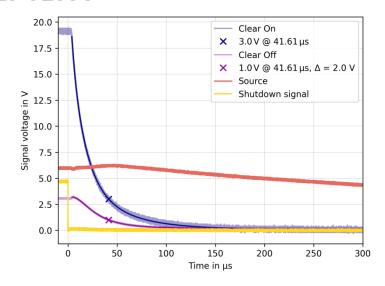




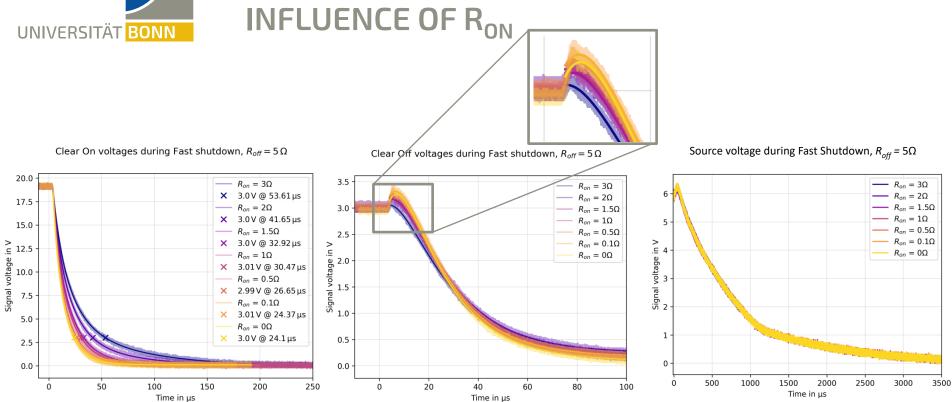


EXEMPLARY MEASUREMENT

- $R_{on} = 2 \Omega$, $R_{off} = 5\Omega$
- 3V-limit
 - Showed earlier: starting at V_{on} = 3V, the modules seemed safe from irradiation
 - Time, at which Clear On voltage drops below 3V
 - Voltage of Clear Off at that time + voltage difference Δ
- Fast-Shutdown board only pulls down Clear voltages -> Source voltage drops much slower







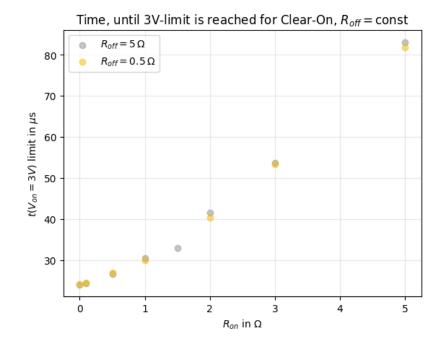


DECAY TIME DEPENDENCE

- 3V-limit for different R_{on} values ($R_{off} = 5\Omega$ or $R_{off} = 0.5\Omega$ fixed)
- Would expect linear behaviour?

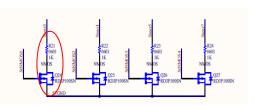
$$U = U_0 * \exp(-\frac{t}{RC}) \rightarrow R = -\ln\left(\frac{3}{19}\right) * \frac{1}{C} * t$$

- Influence of regulator circuit in PS?

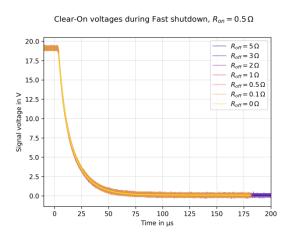


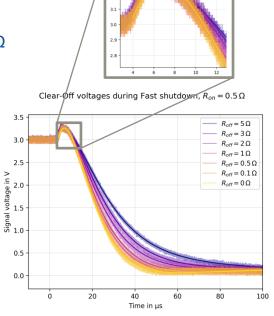


INFLUENCE OF R_{OFF}



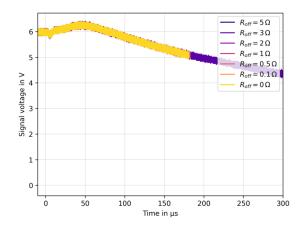
- Pull-Down Resistor studies
- Finished measurements with different R_{on} and R_{off} values
- Here: impact of R_{off} ; $R_{on} = 0.5 \Omega$







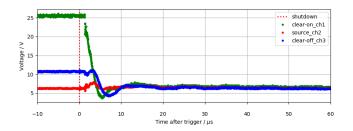




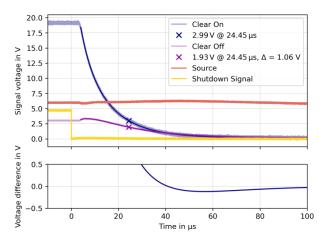


$$V_{ON} < V_{OFF}$$
 ?!

- Asic requirement: Clear On voltage should never drop below Clear Off voltage
- Could be observed in the past for $R_{on} = R_{off} = 0\Omega$
 - Measured on Hybrid5 (full system demonstrator)
 - Not full cable path included → less realistic
- So far: observed with $R_{off} = 5\Omega \& R_{on} < 0.5\Omega$
 - Not as severe as before



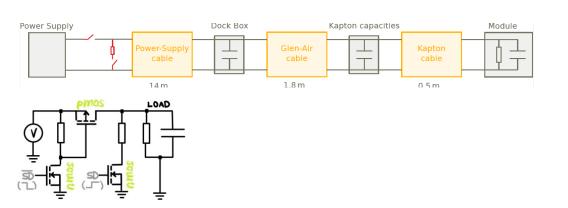
R-test: FAST shutdown | w/ probes ($R_{on} = 0.1 \Omega$, $R_{off} = 5 \Omega$); AGND grounded



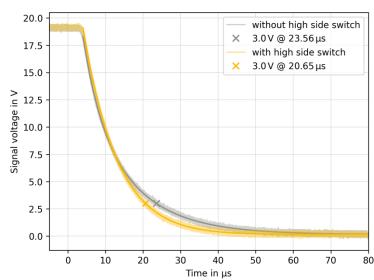


NEW IDEA: HIGH SIDE SWITCH

- Separate PS from load by implementing a switch in series
- Reduce influence of regulator inside of PS
- Shown design only works for positive, high enough voltages
- Pmos steered via nmos
- Faster shutdown of Clear-On voltage due to high side switch?

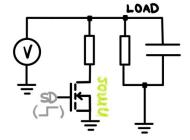


Active shutdown: Clear On vs Source





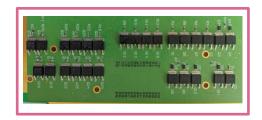
INFLUENCE OF FRONT PCB

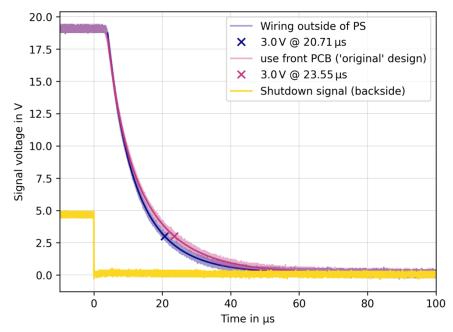


- Sped up fast shutdown seems to come from not using front PCB, not from opening the force line
- Assumptions:
 - Resistance of traces on front PCB?
 - Inductance of traces on front PCB?



VS

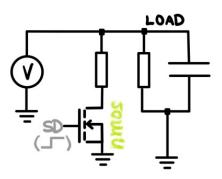




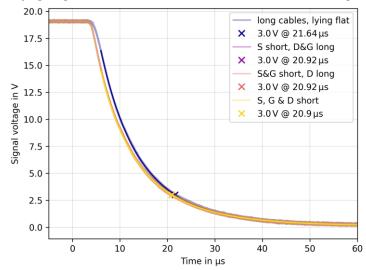


INFLUENCE OF CABLE PARAMETERS

- Test fast shutdown of Clear On with different cable lengths for drain, gate and source of nmos
- Fast shutdown implemented outside of PS, not on fast shutdown board
- Cable length (resistance?) plays a role
- Inductance plays a role, measurements still ongoing



Clear On - Fast shutdown outside of PS; no high side switch varying long cables for Gate (G), Drain (D) and Source (S), AGND grounded





SUMMARY AND CONCLUSION

- Fast shutdown → avoid PXD damage due to beam loss events
- Simulation of PXD powering net
- Descrepancies between simulation and measurement for Power Supply
- Lab-tests:
 - Varying combinations of pull-down resistors
 - Faster transmission of shutdown signal within Power Supply
 - → Test Beam Campaign at MAMI in October 2025?
 - → Production of new Fast Shutdown boards
 - → Installation at KEK (summer 2026?)

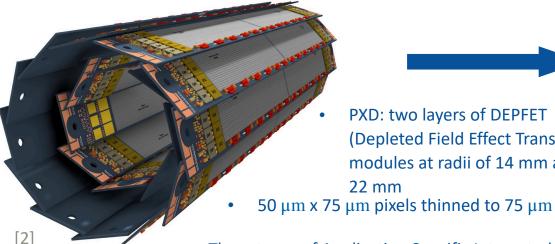
31



THANK YOU!



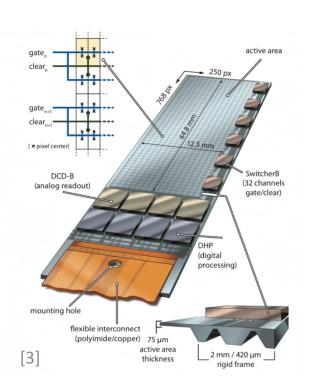
BELLE II PIXEL DETECTOR (PXD)





PXD: two layers of DEPFET (Depleted Field Effect Transistor) modules at radii of 14 mm and 22 mm

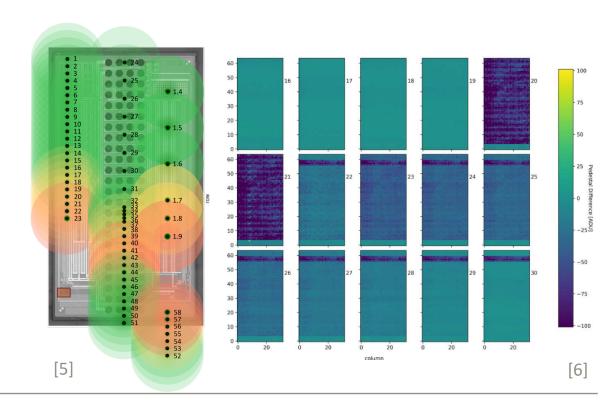
- Three types of Application Specific Integrated Circuits (ASICs) are responsible for readout:
 - DCD, DHP, Switchers





CONFIRMATION OF RESULTS

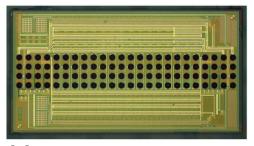
- Irradiation with electron beam
- Fine scan of ASIC area
 - July 2020 with H5029
 - Colour coded measurement points
 - red => permanent damage
- Raw data difference of 15 raw frames during injection
 - Second to last Switcher channel is damaged permanently
- Switcher only vulnerable when turned on

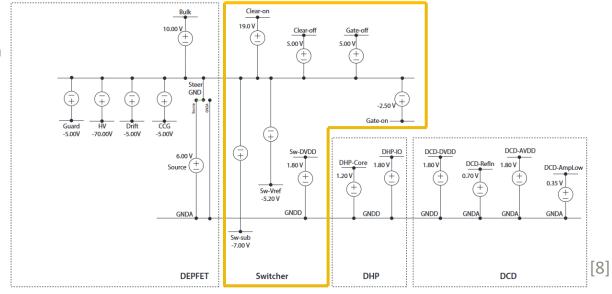




POWERING SCHEME

- Dedicated power-up and power-down sequence
- Range between +19V and -7V
- Switcher switches between high voltages





[7]

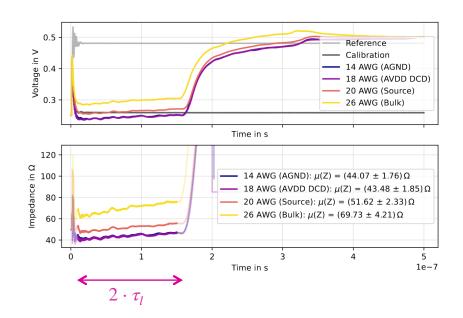


DELAY TIME AND IMPEDANCE

- Needed for Simple Line model (HyperLynx)
- Impedance profile: view cable as cascade of cable segments
 - Reflection at cable connection
 - Average over cable length
 - Rise in impedance due to DC-resistance
- **Delay time**: $\tau_l = (75.5 \pm 0.5) \text{ ns}$

Simple Line

- → HyperLynx
- Impedance
- Delay time
- DC-Resistance

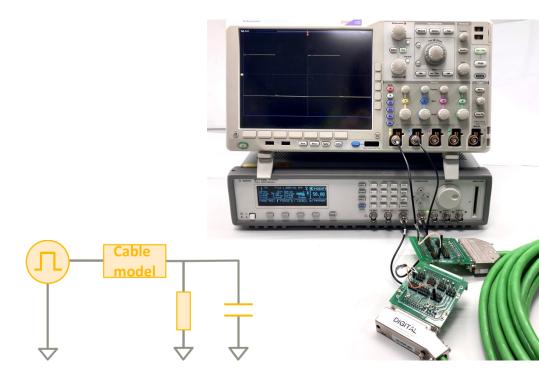






REFERENCE MEASUREMENT

- **Measurement** to compare against simulation
 - Falling edge of a squared pulse
 - View transmitted signal on oscilloscope
- Verify each cable segment individually
- For quantification:
 - Compute difference in voltage between simulation and measurement data





SHUTDOWN PROCEDURE

PASSIVE SHUTDOWN

- Passive shutdown → separate force line from power supply
- Simulate by time dependent resistor which switches from 0 Ω to 100 G Ω
- Time constant in simulation too big

